

Notice of References Cited	Application/Control No. 10/788,542		Applicant(s)/Patent Under Reexamination SCHEER ET AL.	
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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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*	B	US-2007/0243374	10-2007	Lewis et al.	428/349
	C	US-			
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	K	US-			
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NON-PATENT DOCUMENTS

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